

AMENDMENT TO THE SPECIFICATION

Please amend the paragraph beginning on page 9, line 21 as follows:

B1
Chips ~~conventionally~~, chips may include, for example, fifty to one hundred global test control lines to transmit information to anywhere from 5,200 DFT features to 49,000 DFT features. These global test control lines may limit chip designers in the placement and arrangement of the control lines and logical units on chip 300 by taking up valuable space on chip 300. More restrictively, the timing of the signals distributed by each of these global test control lines is critical. As noted below, the invention may reduce the number of global test control lines to nineteen (for example, one bus having nineteen lines) to transmit that same information to the design for test features of a chip.